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Manufacturing AI Problems and Solutions

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1 Why Industrial AI?

2 Computer vision ML for manufacturing

3 Time-series ML for manufacturing

4 Difficulties with time-series ML in manufacturing

5 Gauss Labs success story: Virtual Metrology



"The measure of intelligence is the ability to change." – **Albert Einstein**

Fast AI adoption and absorption by front-runners can create larger economic gains



Note: Numbers are simulated figures to provide directional perspectives rather than forecasts

Relative changes in cash flow by Al-adoption cohort, cumulative % change per cohort



* Source: McKinsey Global Institute Analysis (2019)

"The merit of all things lie in their difficulty." - Alexandre Dumas in The Three Musketeers



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Data-ism

Catch-22

Anna Karenina

Investment



Infrastructure

Data Platforms

Al Ops

Transformative and Integrated Use Cases



Return



"The merit of all things lie in their difficulty." - Alexandre Dumas in The Three Musketeers

Data-ism

Catch-22

Anna Karenina









Every company or sector has its own problems



Computer vision and time-series ML in Manufacturing

lots of image data to measure and inspect

Scanning electron microscope (SEM) images, transmission electron microscope (TEM) images, wafer failure patterns, etc.

 \rightarrow Image pattern classification/clustering, image enhancement, image anomaly detection, defect inspection



(almost) all the data coming from manufacturing are time-series data

sensor data, process times, material measurement, equipment maintenance history, etc.

→ time-series (TS) prediction/estimation, TS anomaly detection, TS classification

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Computer Vision ML for manufacturing



Metrology Measurement of critical features

Inspection Anomaly detection, localization and classification

Image courtesy of ASML



Supervised image denoising



However, it is not possible to acquire ground-truth images from SEM device, in practice.



Blind denoising without ground truth



If the mean of the noise is zero, the average of the gradients that model takes is same with the gradient to the ground truth



Automatic measurement for semiconductor manufacturing



(no. images, tool time, etc.)

Time-series ML for manufacturing



Why time-series ML?

manufacturing application is about one of the following:

- prediction of time-series values virtual metrology, yield prediction
- anomaly detection on time-series data root cause analysis, yield analysis
- classification of time-series values equipment anomaly alarm generation





Time-series prediction and estimation

virtual metrology

- measure unmeasured process materials using equipment signals and other information
- impact: save investment on measurement equipment

yield prediction

- predict yield (# working dies / # total dies) with material measurements from equipment
- impact: better product quality and better profitability





Time-series anomaly detection and root cause analysis

equipment alarm root cause analysis

- when alarm goes off, find responsible equipment and root causes
- impact: reduce equipment downtime, make process engineers' lives easier

- yield analysis
 - find responsible equipment for yield drop
 - impact: 1% yield improvement brings profit increase of tens of millions of dollars!



Difficulties with TS ML in manufacturing



Data challenges

concept drift/shift

 $p(x(t_k), x(t_{k-1}), ...)$ changes over time $p(y(t_k) | x(t_k), x(t_{k-1}), ..., y(t_{k-1}), y(t_{k-2}), ...)$ changes over time

- we have fat data, i.e., # features larger than # data
- poor data quality, i.e., lots of missing values or anomalies
- huge volume of data to process, different types of data



Domain knowledge and fully home-grown algorithms

in most cases, domain knowledge is critical!

close collaboration with customers required

off-the-shelf algorithms not working!

developing fully customized algorithms needed







Gauss Labs success story: Virtual Metrology (VM)



What is VM?

in many cases, we cannot measure all processed materials

- measurement equipment is too expensive
- measuring every materials makes production slow inducing low throughput

thus, we do sampling (with very low sampling rate)

• in semiconductor manufacturing line, average sampling rate is less than 1%

PROBLEM

- predict the measurement of unmeasured material using indirect signals
- sensor data, maintenance history, operation data, . . .

Sensor data, maintenance history, operation data, ...

process

Al Model (semi-supervised learning)





10x change made by VM

To the best of our knowledge

 no organization has even been successful with VM

Gauss Labs VM

- uses online learning to cope with data drift/shift
- RMSE comparable to measurement equipment precision
- also predicts uncertainty of predictions - providing prediction reliability information

VM implications

- measuring ALL wafers equivalent to investing on 100x measurement equipment
- enables optimal re-allocation of limited measurement resources



Conclusion

supervised and unsupervised ML everywhere in industrial AI applications lots of challenges

 data challenge, domain knowledge required, need for customizing algorithms 10x changes potentially made via various applications

Impacts

- Tens of Millions of dollars by 1% yield increase
- 100x measurement equipment save by VM

Gauss Labs has success stories include

- Virtual Metrology (VM)
- Subnanometer-precision Machine Vision



Who we are



Founded in Silicon Valley and Seoul, Korea, in August 2020 Strategic investment of \$55m by SK

SCAN here For info





Global team of ~45 Gaussians (grow with quality and speed) Top talents from global companies (16 PhDs)



Mission of innovating industry with trustworthy AI technologies Reliable, robust, and scalable AI products and solutions for 10x changes





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We normalize AI.